

<b>Notice of References Cited</b>	Application/Control No. 10/528,112	Applicant(s)/Patent Under Reexamination KURITA ET AL.	
	Examiner William J. Klimowicz	Art Unit 2627	Page 1 of 3

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	Examiner William J. Klimowicz	Art Unit 2627	Page 2 of 3

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KURITA ET AL.

Examiner

William J. Klimowicz

Art Unit

2627

Page 3 of 3

**U.S. PATENT DOCUMENTS**

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